

Measurement of the volt-ampere characteristic of SiPM on wafer level with setup based on PA200 BlueRay probe station

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Setup for measurement of the volt-ampere characteristics of SiPMs on wafer level consists of probe station PA200 BlueRay, source-meter Keithley 2400 and computer. Controlling of the setup performed by special program which allows tune the accuracy and speed of the measurement by selecting averaging mode and integration time of Keithley 2400 and by constructing the custom logic of the measurement.

Primary author(s) : POPOVA, Elena (MEPhI)

Co-author(s) : STIFUTKIN, Aleksei (MEPhI); KAYUMOV, Fred (Lebedev Physical Institute); BUZHAN, Pavel (MEPhI)

Presenter(s) : KAYUMOV, Fred (Lebedev Physical Institute); BUZHAN, Pavel (MEPhI)

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